X-Ray Microtomography as a Nondestructive Tool for Characterization of Thermal Sprayed Ceramic Deposits

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Introduction: Computed Microtomography (CMT) has been explored to elucidate microstructure-property correlations in thermal sprayed ceramic deposits. Pores and cracks in freestanding deposits have been characterized using the synchrotron x-ray source at X27A Beamline at BNL. The effects of processing techniques (air and vacuum plasma sprayed (APS & VPS) and high velocity oxy-fuel (HVOF) process) and feedstock characteristics (powder precursor and morphology) on microstructure development in the coatings have been investigated. Coatings of alumina based systems (Al₂O₃, Al₂O₃-13% TiO₂ and Al₂O₃-25% MgO spinel) have been examined. Thermal, dielectric and mechanical properties of the coatings have been correlated to microstructural features observed. Studies have been carried out on as-sprayed and heat-treated coatings to observe microstructural changes and its influence on properties. CMT measurements have shown that HVOF deposits have flat, in-plane layered pores, where-as the plasma sprayed coatings display globular pores. These results have explained in a dramatic fashion the apparent anomalous difference between thermal conductivity for HVOF and plasma sprayed coatings [1].

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References: Kulkarni A. *et. al.*, "Computed microtomography studies to characterize microstructure-property correlations in thermal sprayed alumina deposits." <u>Scripta Mat</u>. 43 (2000) pp 471-476.